

Wafer datasheet

Star120

(900V/120A)

Features

GaNPower innovative all-GaN-IC enables 3.8V turn-on voltage and +/-20 V regulated gate driving. Enhanced system reliability and compatibility with conventional gate drivers.

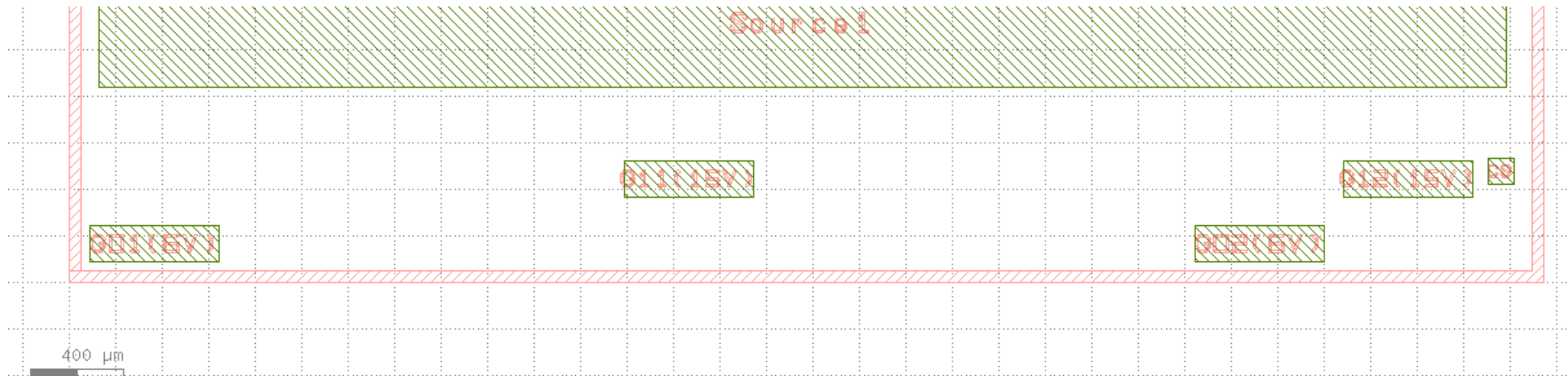
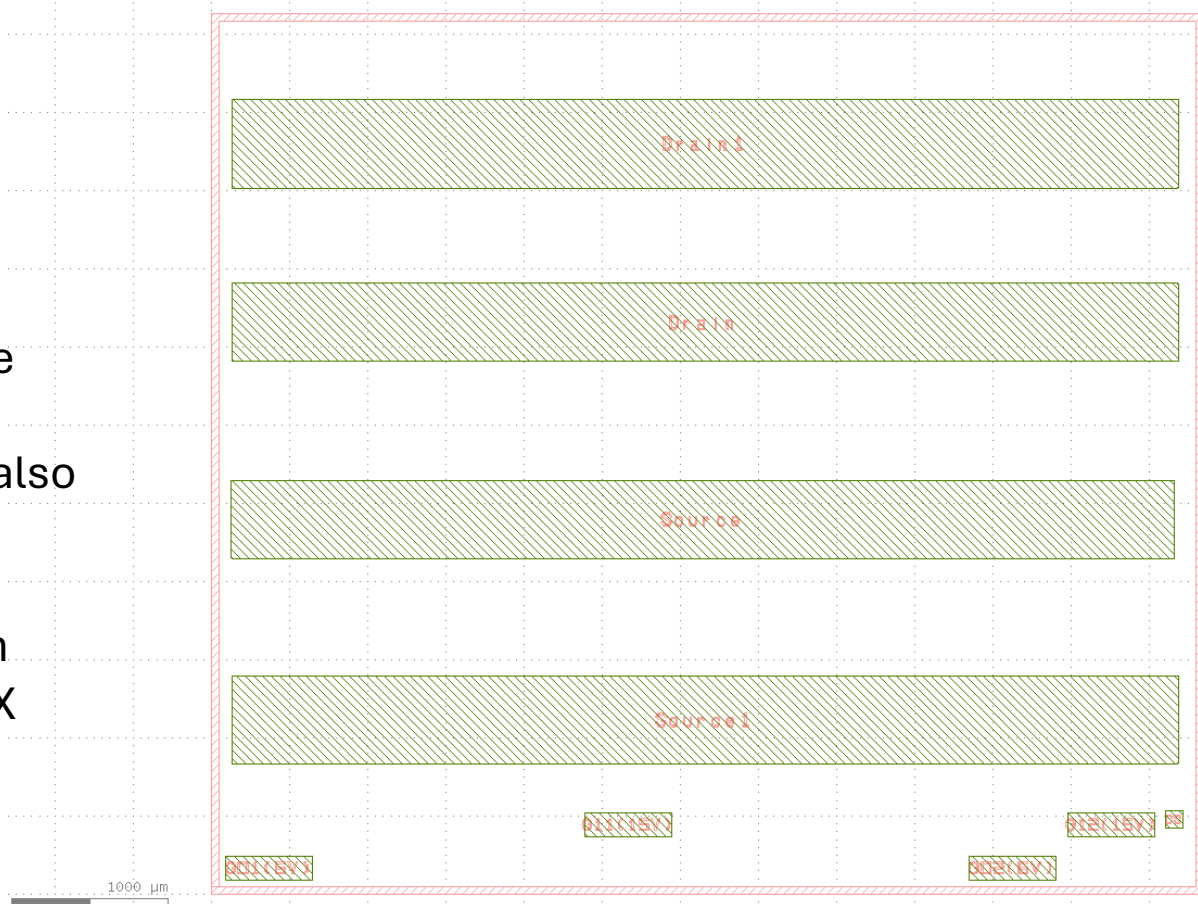
Regulated gate driving enables anti-ringing Protection / ESD protection

Lossless source side current sensing

Device-name	x-size	y-size
Star120	6345.90	5634.28

Note that G11(15V) and G12(15V) are internally connected.
 Similarly, G01(6V) and G02(6V) are also internally connected.

For best gate control uniformity, both G1X (for 12/15V driving) or both G0X (for 6V driving) shall be used if wire bonding configuration allows.



Main switch FET channel width: 1,426,822 um

PAD	Dx	Dy	Center_x	Center_y
G01(6V)	555.00	155.00	368.30	168.30
G11(15V)	585.00	185.00	2664.55	446.30
Source	6032.72	500.00	3144.16	2397.14
Source1	6053.72	560.00	3156.66	1116.70
Drain	6053.72	500.00	3156.66	3657.14
Drain1	6053.72	567.00	3156.66	4799.98
CS	111.00	111.00	6158.02	479.30
G02(6V)	555.00	155.00	5121.95	168.30
G12(15V)	585.00	185.00	5759.20	446.30

Basic specifications

Back metal	None
Front metal	AlCu 4um
Wafer diameter	6 inch
Wafer thickness before dicing	1000 um
Recommended die thickness after dicing	250-300um
Street width	80 um
Recommended storage	N2 environment

Wire bonding suggestion

Larger pads use 10mil or 12mil Al .

Smaller pads use Cu, PdCu , or Au (1.5 mil – 2 mil)

Backside must be glued to backplate using conductive glue

Backplate must be connected to the source of the GaNFET using wire bonding

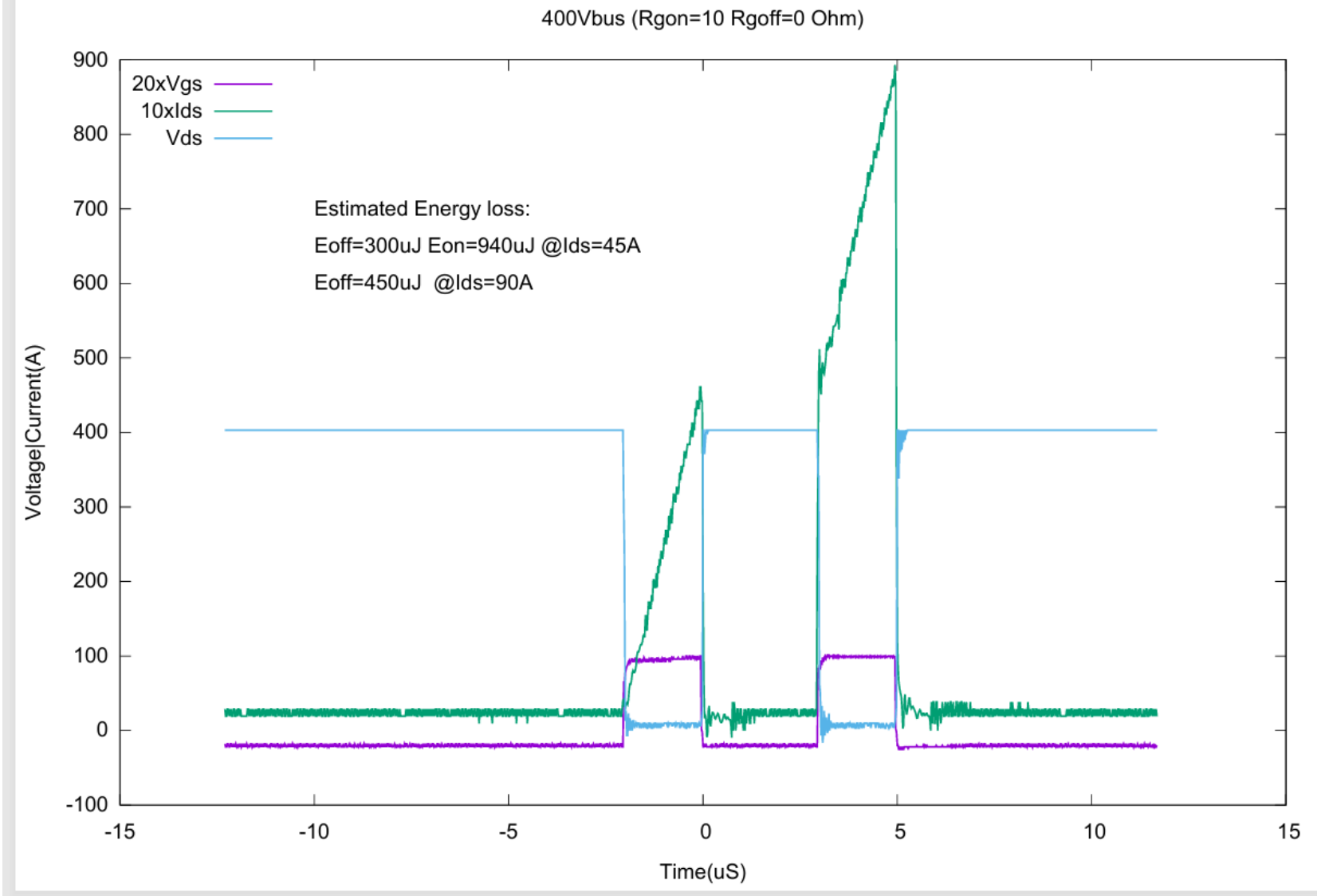
Characteristics

		Condition	min	typical	max	
I _{ds} -max	Max current at 125C	V _{gs} =6/15 125C		120		A
I _{ds} -max	Max current at 25C	V _{gs} =6/15 25C		240		A
V _{ds} -max	D-S breakdown voltage	V _{gs} =0 25C < 10uA		900		V
V _{g0s}	Original gate voltage		-3		7	V
V _{g1s}	Regulated		-20		20	
V _{gth} (G0)	Gate threshold voltage	V _{gs} =V _{ds} I _{ds} =35mA		1.3		V
V _{g1th_lin} (G1)	Regulated threshold	V _{ds} =0.01V, I _{ds} =100 mA	2.64	3.95	5.26	V
V _{g1th_sat} (G1)	Regulated threshold	V _{ds} =0.01V, I _{ds} =100 mA		2.09	3.75	V
R _{dson}	On resistance	V _{g0s} =6/V _{g1s} =15 I _{ds} =1A 25C	8.4	12	16	mOhm
R _{dson} (150C)	On resistance	V _{g0s} =6/V _{g1s} =15 I _{ds} =1A 150C	18	26	34	mOhm
V _{cs}	Current sensing	I _{ds} =+/-120A	-2.5		2.5	V
Q _g	Gate charge	V _{bus} =500V Turn-off from I _{ds} =60A V _{g0s} from 6 to 0 25C		29		nC

		Condition	min	typical	max	
Gm-Max	Max transconductance		360	650		mS
IDSS	Drain leakage	Vg1s=0 / Vg0s=0 Vds=800 25C		3.8	10	uA
IDSS(150C)	Drain leakage	Vg1s=0 / Vg0s=0 Vds=850 150C		19	75	μA
IDSS(150C)	Drain leakage	Vg1s=0 / Vg0s=0 Vds=900 150C		33	85	μA
IGSSF	Forward gate leakage	Vg1s=6 Vds=0 25C		670	5500	μA
-IGSSR	Reverse gate leakage	Vg1s=-6 Vds=0 25C		0.2	0.8	μA
-IGSSR(150C)	Reverse gate leakage	Vg1s=-6 Vds=0 150C		131	930	uA
Max_Isoff	Source leakage	Vg=Vs=Vb=GND, Vd=800V		0.6	7	μA
Isub	Bulk/substrate leakage	Vs=Vg=Vd=800V, B=GND		4.3		μA

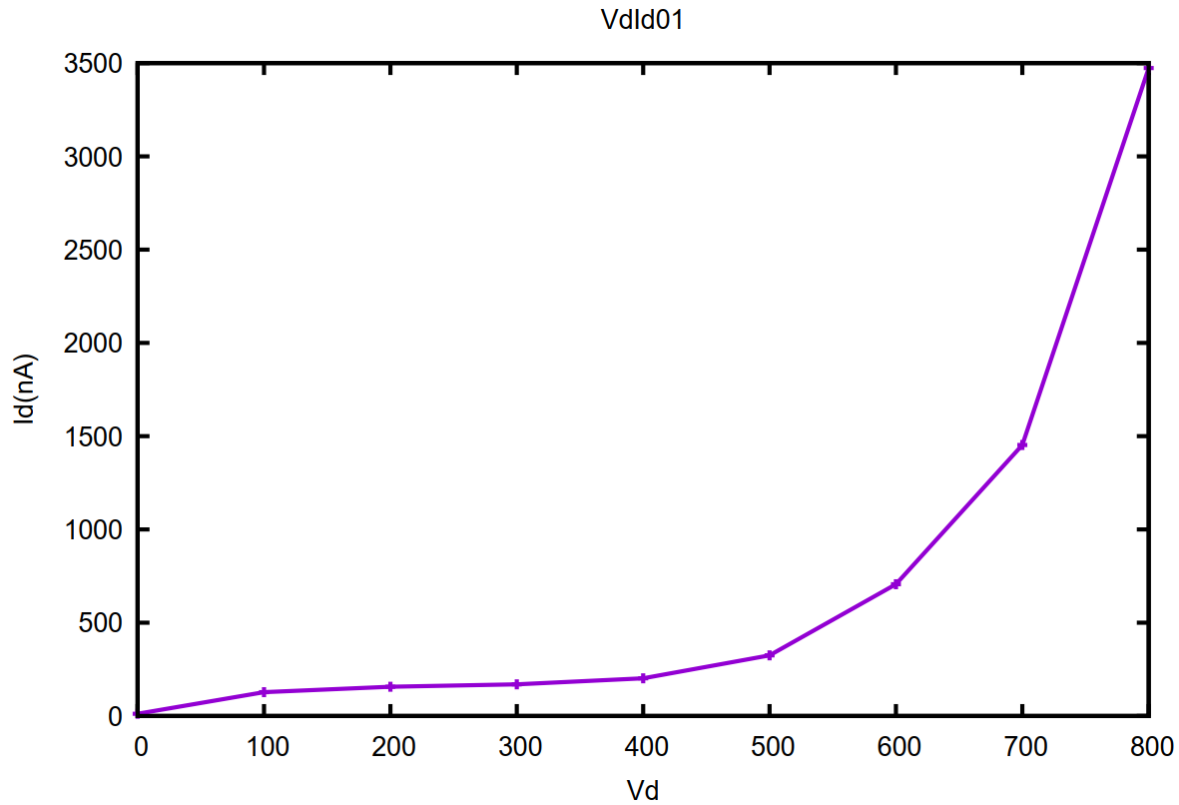
Gate pulsing test at 200KHz (4 uS on /1 uS off)

VG1(-)	VG1(+)	VG0(-)	VG0(+)	VBUS
-1.3	11.6	-0.7	7.4	0
-3.4	11.6	-3.1	7.4	0
-6.3	11.6	-6.3	7.4	0
-3.4	11.6	-3.0	7.4	100V (1.5A)
-3.4	11.6	-2.9	7.4	200V (2.1A)
-3.4	11.6	-2.8	7.4	400V (4.5A)

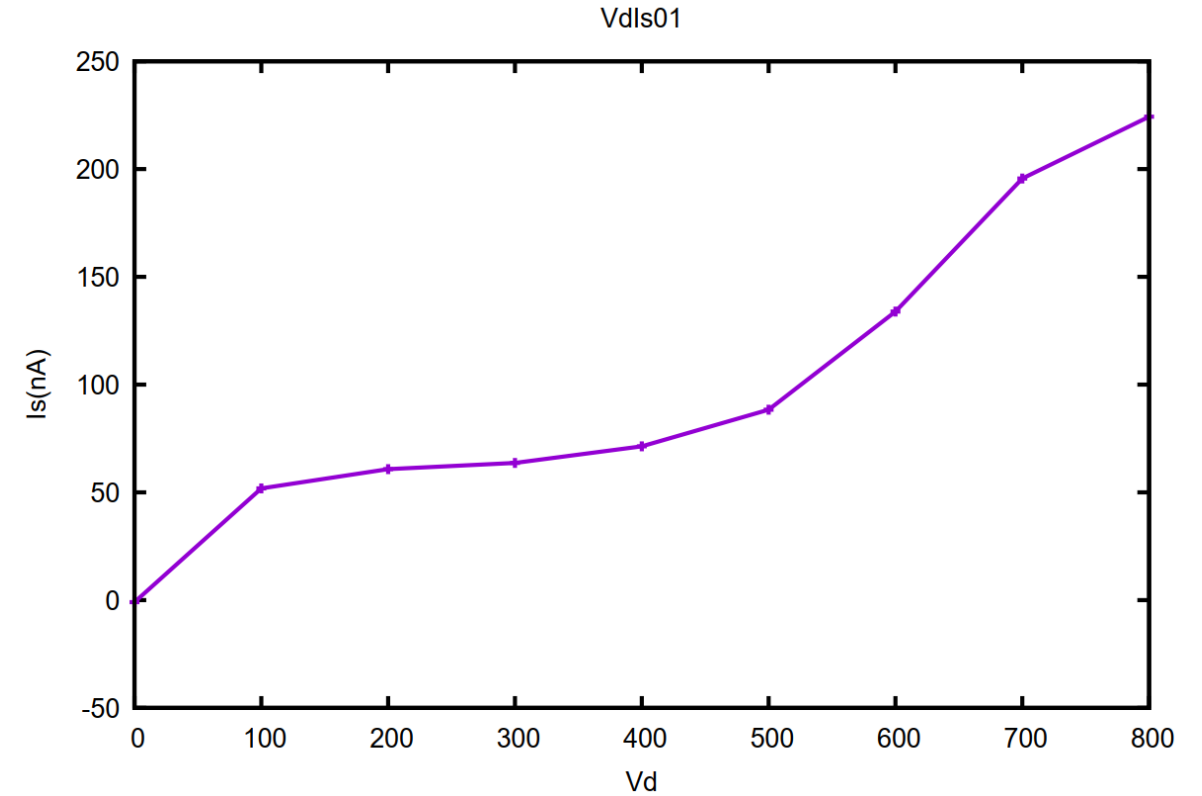


Dynamic test using TO247-4 package
 For more realistic evaluation of power integral, ringing in $I_{ds}(t)$ data have been eliminated by peak to peak averaging.

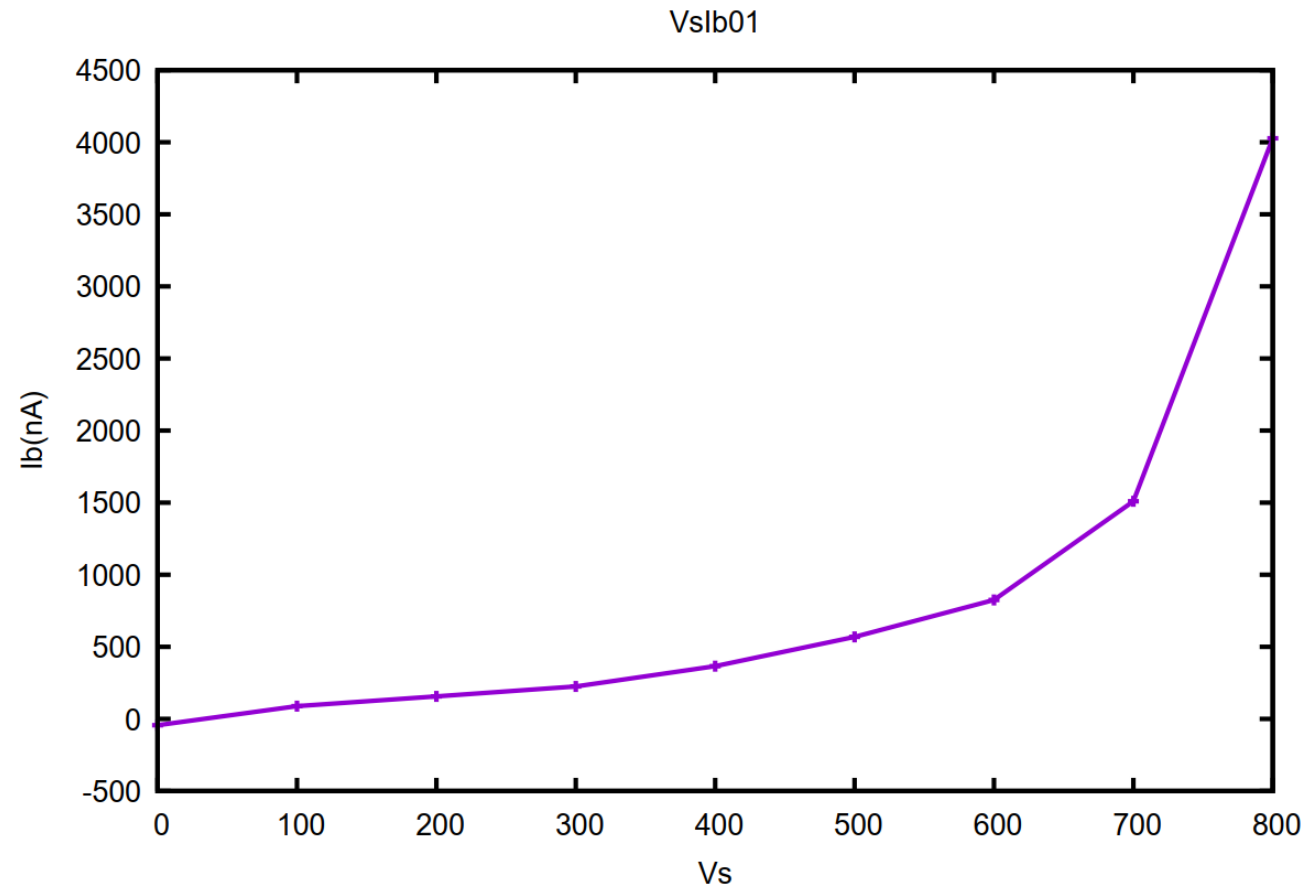
@RT



**Drain leakage I_{dss} versus V_{ds}
@ $V_g=V_s=V_b=GND$**

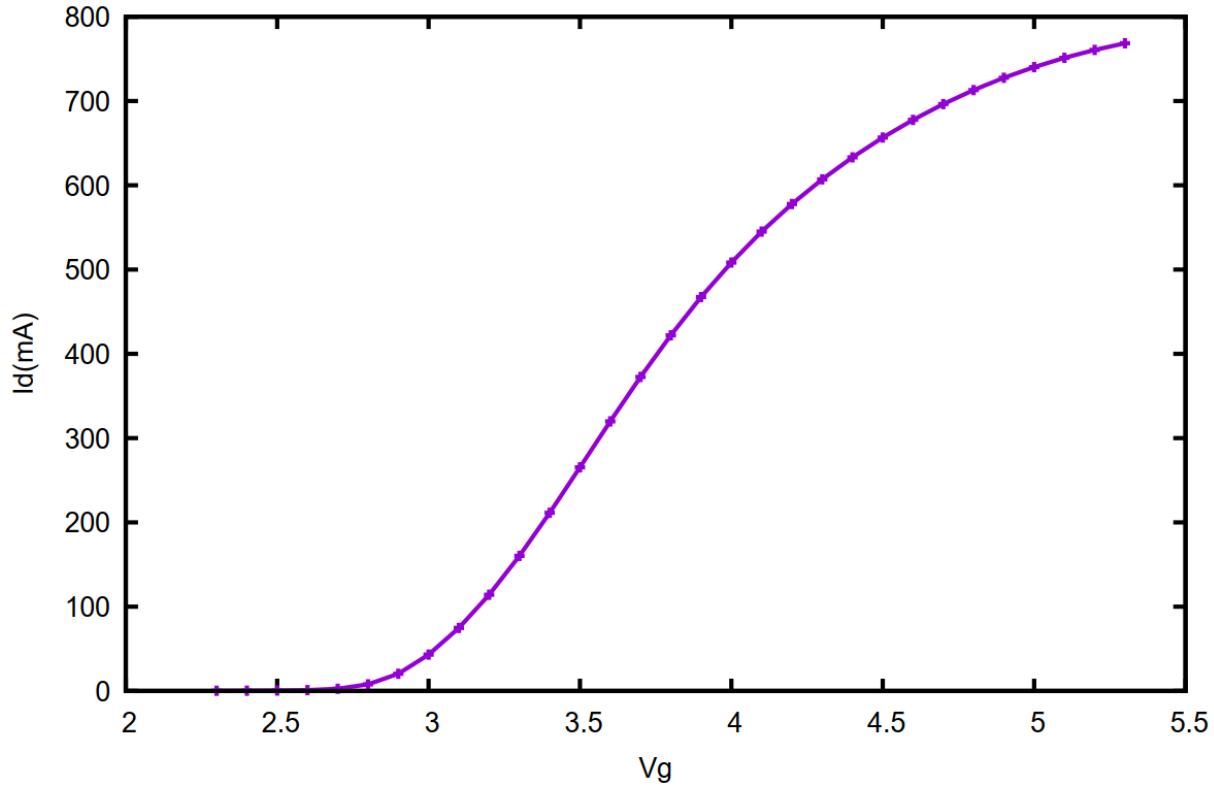


**Source leakage I_s versus V_{ds}
@ $V_g=V_s=V_b=GND$**



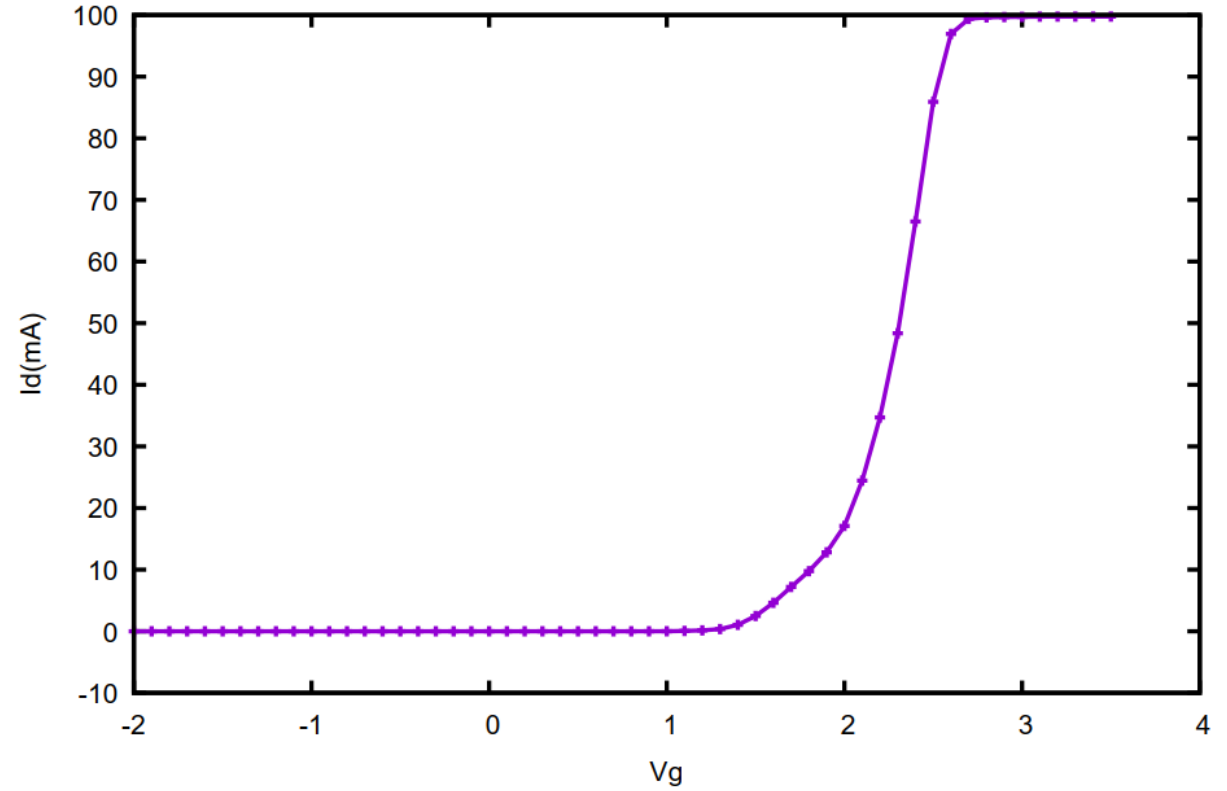
**Bulk (Substrate) leakage I_b versus V_s
@ $V_g=V_s=V_d$, B=GND**

VgId03

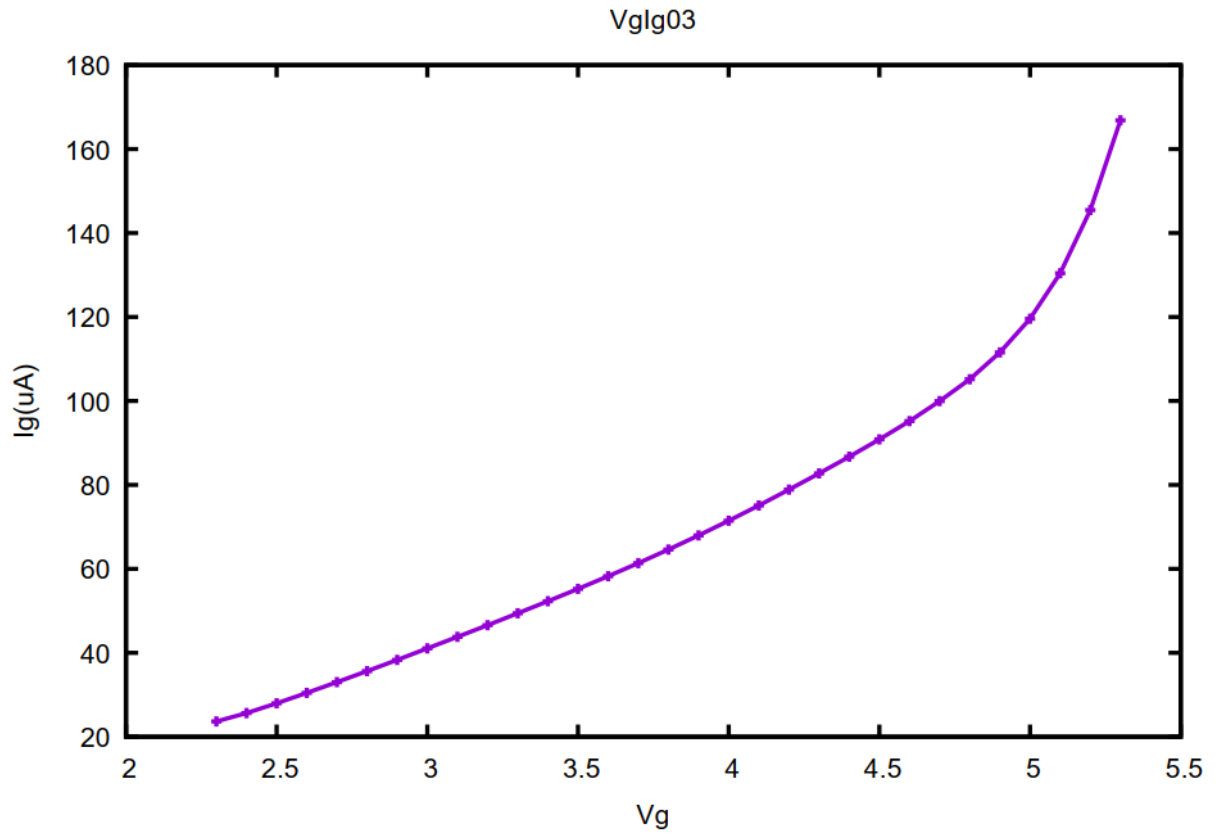
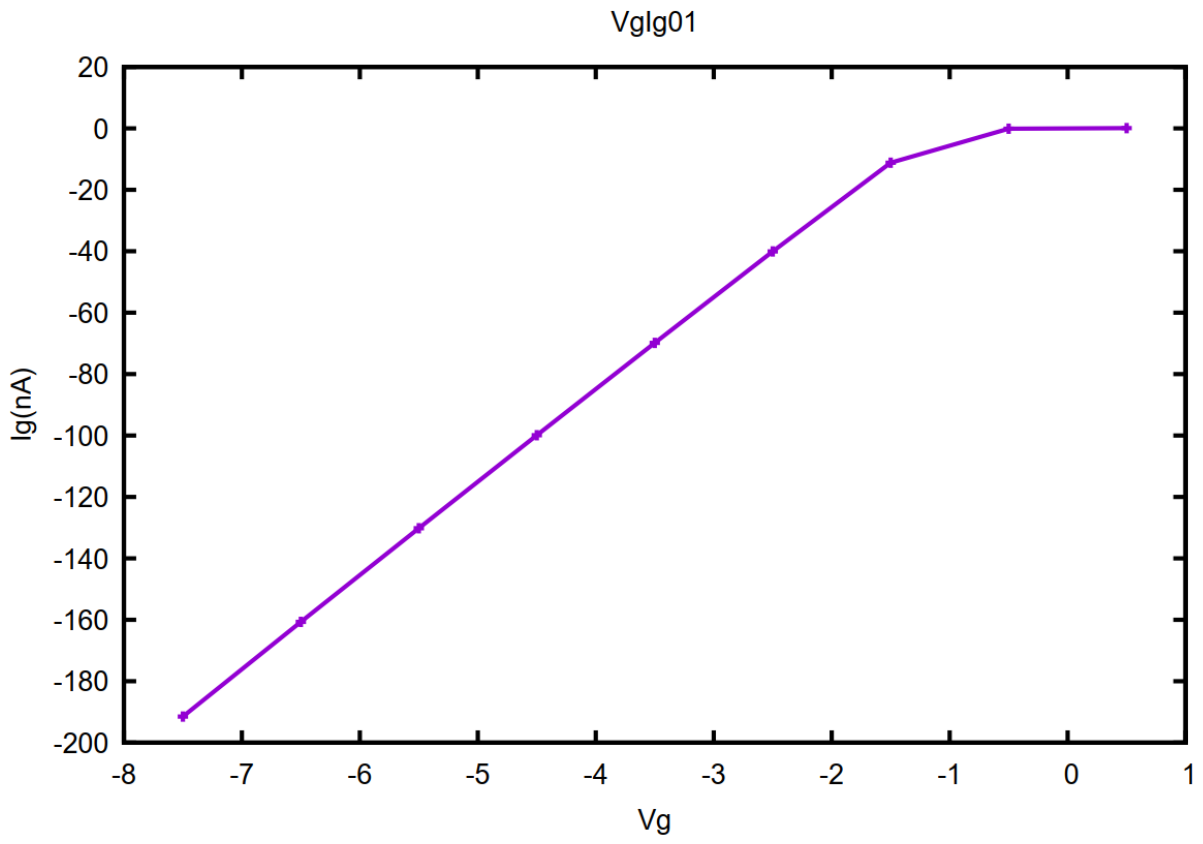


Id-Vg transfer curve
@Vds=0.01V, Vs=Vb=GND

VgId04

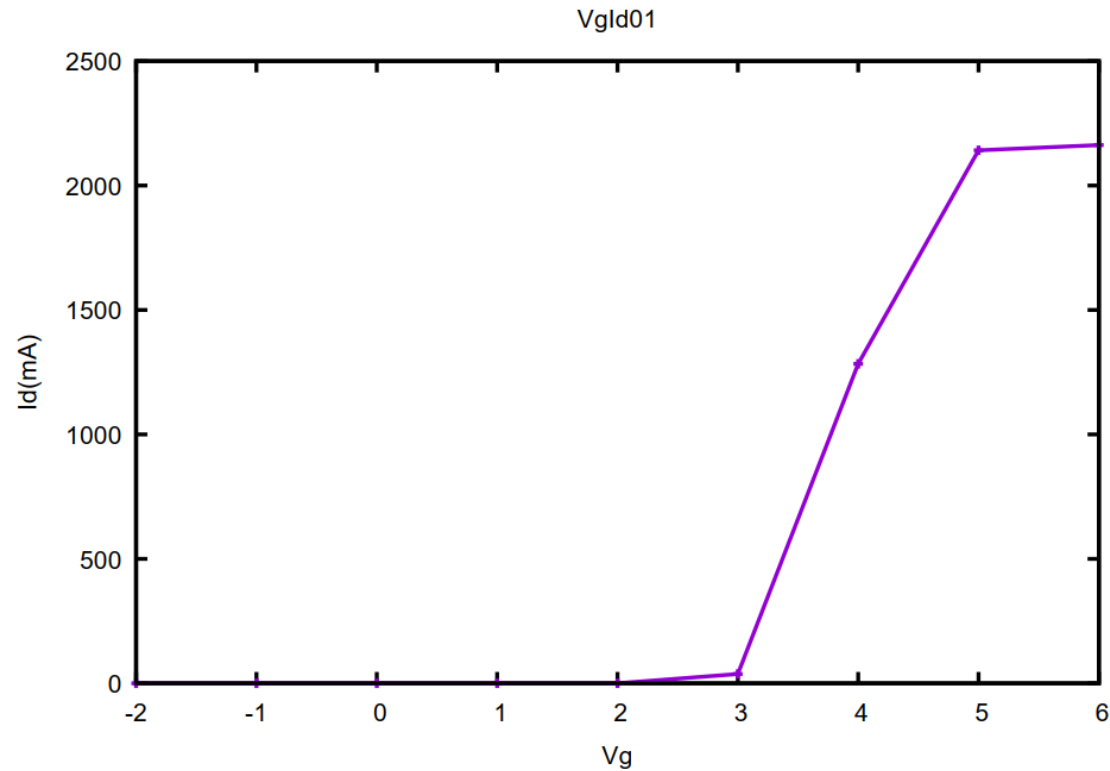


Id vs Vg transfer curve
@Vds=100V, Vs=Vb=GND

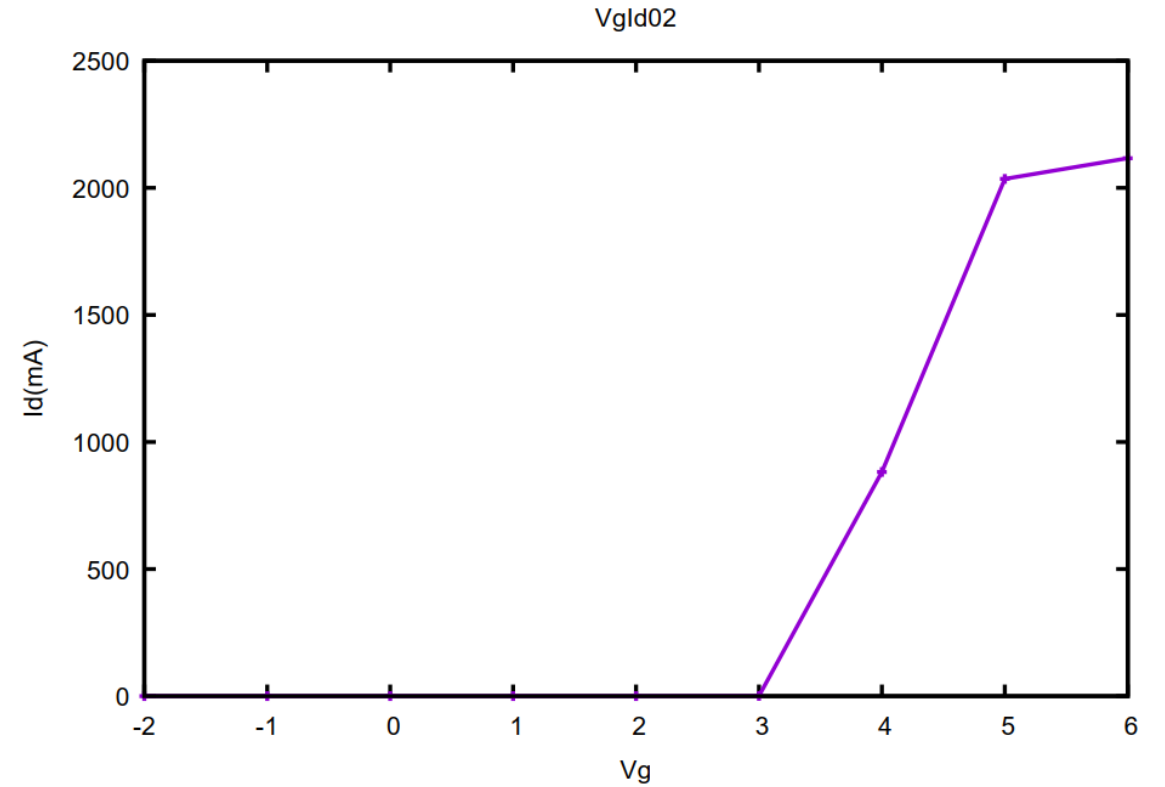


Gate leakage
@ $V_{ds}=0.1$ V, $V_s=V_b=GND$

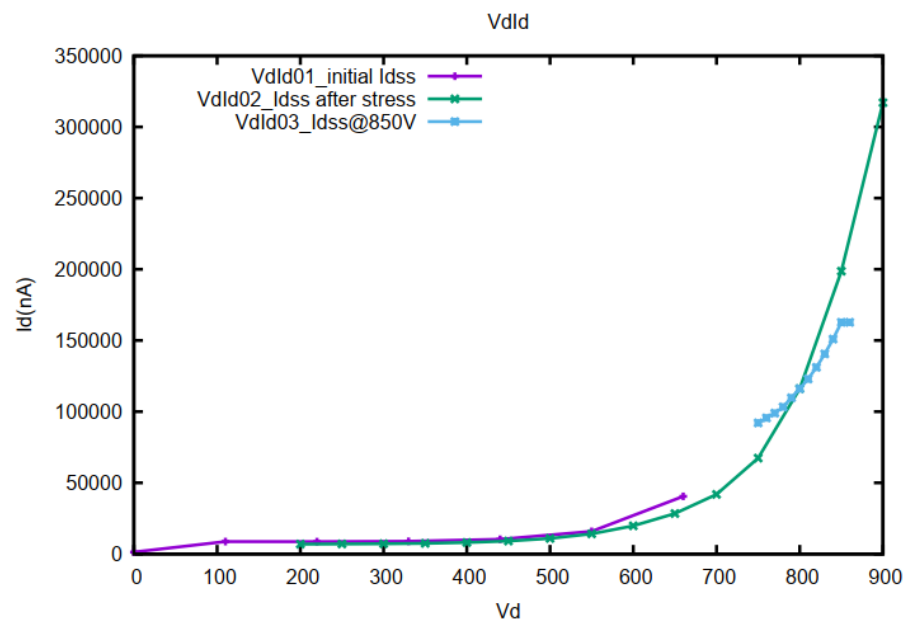
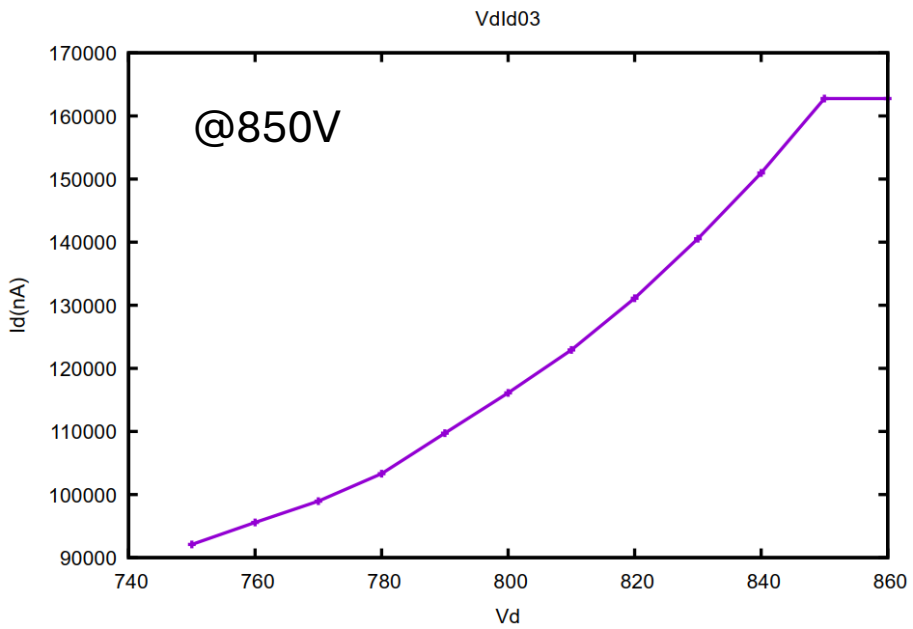
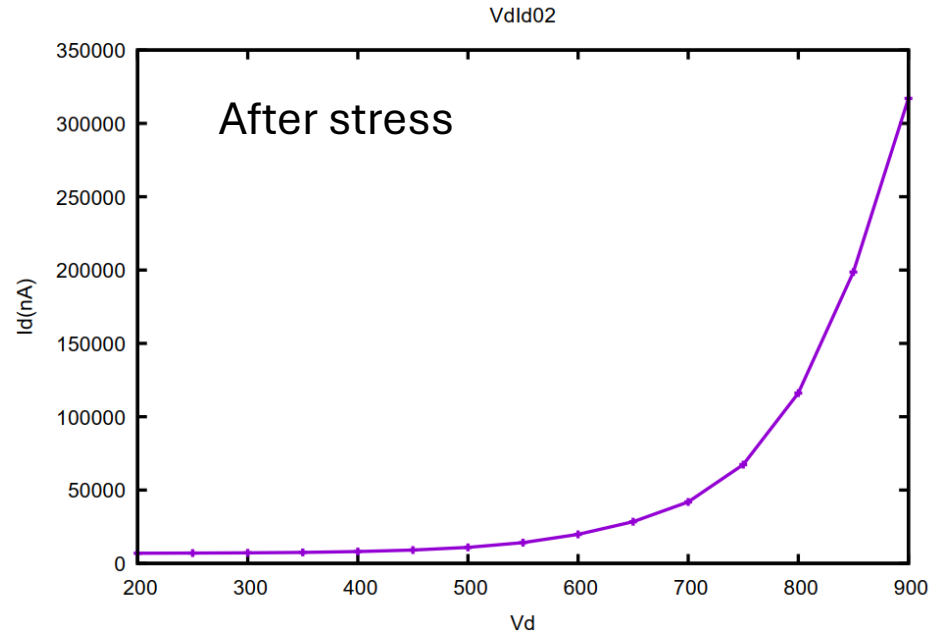
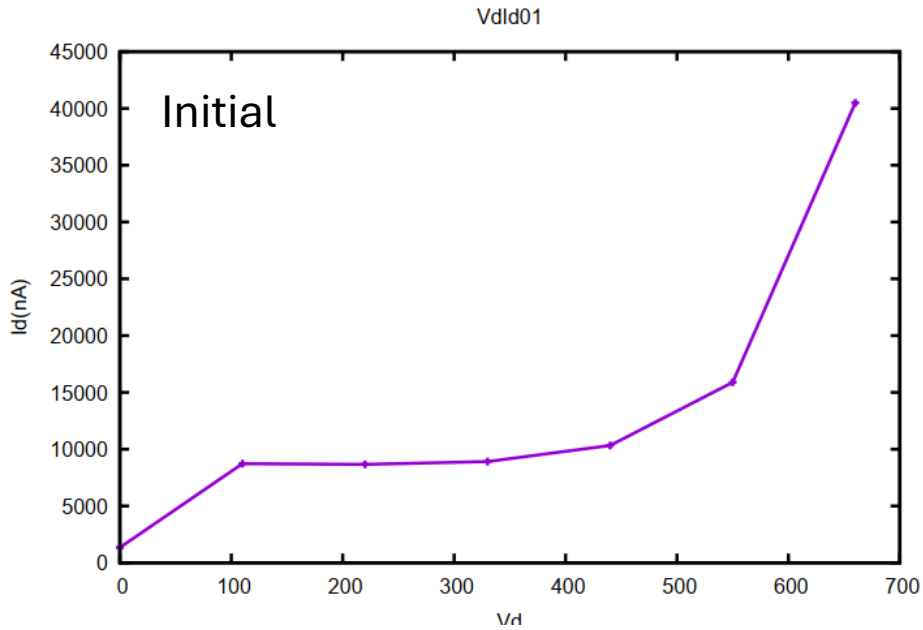
@HT 150 °C



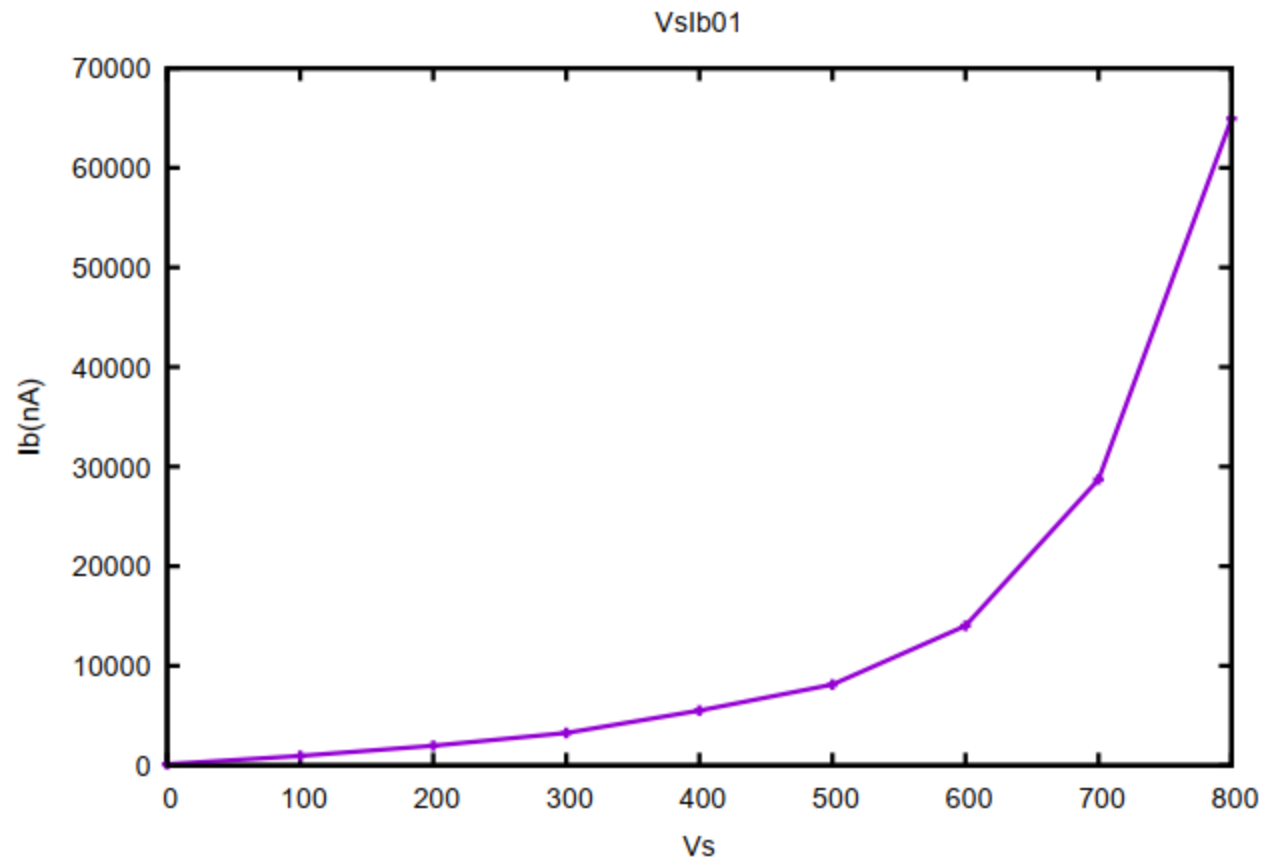
Id-Vg transfer curve, initial @Vds=0.1V



Id-Vg transfer curve, after stress @Vds=0.1V



Drain leakage Idss versus Vd @Vg=Vs=Vb=GND



**Bulk/substrate leakage I_b versus V_s
@ $V_g=V_s=V_d$, B=GND**

Application note on G1 (15V) driving

Negative Gate Turn-off

As with most EMODE GaNFET, it is best to use negative turn off gate driving to achieve fast turn off. In such a case, G0 can be left not connected (NC). Negative gate voltage of -1 to -3 are recommended.

Zero Gate Turn-off

When using G1 for driving (either 0-12V or 0-15V), it is best to wire bond a bare die of low voltage diode (max rating 20V, max current 0.5A) between G0 and G1 such that the forward direction of the diode points from G0 to G1. Caution: at light loading (less than 0.5A), turn-off may be slow.

Recommended $R_{goff}=0$ $R_{gon}=0$ to 5 Ohm. Recommended driver: 1EDBX275F, or other driver with stronger current capability. It is also possible to drive multiple devices/dies at parallel. When parallelizing more than three Star120, paralleled multiple-driver is recommended.

Application note on G0 (6V) driving

G0 can be used as a standard EMODE p-GaN gate. Recommended $R_{goff}=0$ $R_{gon}=5-10$ Ohm

Choice of G1 or G0:

For better system reliability, G1 is recommended.